## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:	
Simon BATES et al.	) Group Art Unit: 4112
Application No.: 10/590,204	) ) Examiner: Bryan T. Kilpatrick \
Filed: August 22, 2006	Confirmation No.: 5565
For: ANALYSIS AND SCREENING OF SOLID FORMS USING THE ATOMIC PAIR DISTRIBUTION FUNCTION	) ) )

U.S. NATIONAL PHASE OF INTERNATIONAL APPLICATION NO. PCT/US2005/006114

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

## **INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)**

Pursuant to 37 C.F.R. §§ 1.56 and 1.97(b), Applicants bring to the attention of the Examiner the listed documents on the attached PTO SB/08 Form. This Information Disclosure Statement is being filed before the mailing date of a first Office Action on the merits for the above-referenced application.

Copies of the listed non-patent literature documents are attached.

Applicants respectfully request that the Examiner consider the listed documents and indicate that they were considered by making appropriate notations on the attached form.

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that each or all of the listed documents are material or constitute "prior art." If the Examiner applies any of the

Attorney Docket No. 09013.0010 Application No. 10/590,204

documents as prior art against any claim in the application and Applicant determines that the cited documents do not constitute "prior art" under United States law, Applicants reserve the right to present to the U.S. Patent and Trademark Office the relevant facts and law regarding the appropriate status of such documents.

Applicants further reserve the right to take appropriate action to establish the patentability of the disclosed invention over the listed documents, should one or more of the documents be applied against the claims of the present application.

If there is any fee due in connection with the filing of this Statement, please charge the fee to Deposit Account No. 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW, GARRETT & DUNNER, L.L.P.

Ernest F. Chapman

Reg. No. 25,961

Dated: May 4, 2007

IDS Form PTO/SB/08: Substitute for form 1449A/PTO

Sheet

## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

1 of 1

Complete if Known			
Application Number 10/590,204			
Filing Date	August 22, 2006		
First Named Inventor	Simon BATES		
Art Unit	4112		
Examiner Name	Bryan T. Kilpatrick		
Attorney Docket Number	09013.0010		

	Cite		Issue or	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where	
Initials	No.¹	Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY		Relevant Passages or Relevant Figures Appear	
/B.K./	1	US-2004/0103130 A1	27 MAY 2004	Ivanisevic et al.		
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Note: Submission of copies of U.S. Patents and published U.S. Patent Applications is not required.

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.1	Foreign Patent Document  Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> ( <i>if known</i> )	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation <sup>6</sup>
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NONPATENT LITERATURE DOCUMENTS				
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/B.K.	2	Peterson, P.F., et al., "Improved measures of quality for the atomic pair distribution function," J. Appl. Cryst. 36, pp. 53-64, (2003).		
/B.K./	3	SSCI, "Software," pp. 1-12.		
/B.K.,	4	SSCI, "Analysis of disordered materials using XRPD and PDF transform: micro-crystalline - true amporphous?," pp. 1-17.		
/B.K./	5	Sheth, A.R., et al., "Polymorphism in Piroxicam," American Chemical Society, Crystal Growth & Design, 0, pp. 1-8, (April 2, 2004).		
/B.K./	5	E. Takeshi, "PDF analysis applied to crystalline materials," Local Structure from Diffraction, pp. 1-21 (1998).	. 202	
/B.K./	6	H. Drozdowski, "The molecular structure of liquid 1-phenylnaphthalene by X-ray diffraction, acta phsica slovava, Vol. 51, No. 2, pp. 163-174 (April 2001).		
/B.K./	7	SSCI, "XRPD pattern analysis: from matching to molecular imaging," pp. 1-23.		

Examiner Signature	/Bryan Kilpatrick/ (07/20/2008)	Date Considered	07/20/2008

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.